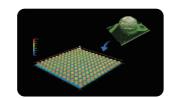
MMD-CON SERIES

NON CONTACT ROUGHNESS PROFILER





Silicon wafer surface morphology



Surface morphology of product coating



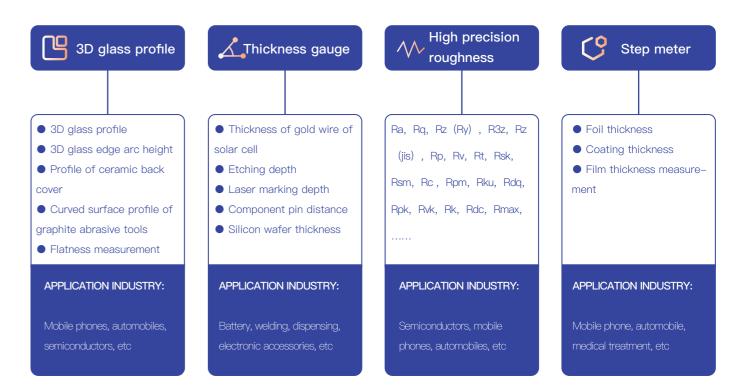
Mobile phone central control and precision accessories



Optical lens

It is widely used in the measurement of product geometric dimensions and surface morphology, such as product coating surface morphology, silicon wafer surface morphology measurement, mobile phone central control and precision accessories, optical lenses, auto parts and other fields.

MEASUREMENT FUNCTION



TECHNICAL PARAMETER

	3D glass profile	Thickness gauge	High precision roughness	Step meter
Z direction range	100mm			
Measuring range in XY direction	100mm×100mm			
Z1 measuring range	3mm		0.7mm	
X-axis scanning accuracy	< (0.6+0.006L) µm			
Indication accuracy	1µm		5nm	0.2µm
resolving power	6nm		2nm	
Working distance	16mm		10mm	
Measurement method	X-direction scanning			
Measuring frequency	4000Hz			
load bearing	10Kg			



MEASURABLE WORKPIECE



















MEASUREMENT EXAMPLES

